



THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09,388,826  
Filing Date ..... September 1, 1999  
Inventor ..... Weimin Li, et al.  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2813  
Examiner ..... E. Kielin  
Attorney's Docket No. .... MI22-1208  
Title: Low k Interlevel Electric Layer Fabrication Methods

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56.  
Copies of the cited prior art references are attached. No admission is made regarding  
whether the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: Nov 15, 2001

By: Bernard Berman

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1208SERIAL NO.  
09/388,826LIST OF ART CITED BY APPLICANT  
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Weimin Li et al.FILING DATE  
September 1, 1999GROUP  
2813

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,801,399	9/98	Hattori et al.			
AB	5,994,730	11/99	Shrivastava et al.			
AC	6,040,619	3/00	Wang et al.			
AD	6,060,765	5/00	Maeda			
AE	6,060,766	5/00	Mehta et al.			
AF	6,133,613	10/00	Yao et al.			
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EXAMINER

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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.